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PRODUCT SPECIFICATION

DDR4 DIMM SOCKET

1.0 SCOPE

This Product Specification covers the 0.85mm centerline gold plated DDR4 DIMM edge card connector for 1.40 ± 0.10 thick memory modules.

2.0 PRODUCT DESCRIPTION

2.1 PRODUCT NAME AND SERIES NUMBER(S) <u>Series Number</u> 151080 DDR4DIMM 25° THROUGHHOLE 0.76Au 288CKT

2.2 DIMENSIONS, MATERIALS, PLATINGS AND MARKINGS

See the appropriate sales drawing(s) for information on dimensions, materials, plating and markings, on recommended module outlines and footprint specifications.

2.3 SAFETY AGENCY APPROVALS

- UL File Number TBA
- CSA File Number TBA

TEN	ITATIVE RELEASE:				
THI	S SPECIFICATION IS B	ASED ON DESIGN OBJ	ECTIVES AND IS STRI	CTLY TEN	TATIVE.
PRE	LIMINAKY TEST DATA	NMAY EXIST, BUT THIS	SPECIFICATION IS SU		010
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2	<u>LO NO.</u> 32013-0772	DDR4 D	IMM, 0.85mm PIT	CH	1 of 7
	<u>DATE:</u> 2014/11/20	25°, TH	RU-HOLE, 288CK	T	
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3.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

Refer to the appropriate sales drawing(s) and other sections of this specification for the necessary referenced documents and specifications. In the event of conflict between the requirements of this specification and the product drawing(s), the product drawing(s) shall take precedence. In the event of conflict between the requirements of this specification and the reference documents, this specification shall take precedence.

4.0 RATINGS

4.1 VOLTAGE

29 Volts AC (RMS) / DC

4.2 CURRENT

0.75 Amps / pin

4.3 TEMPERATURE

Operating: - 55°C to + 85°C Nonoperating: - 55°C to + 85°C

4.4 FIELD LIFE AND TEMPERATURE

Field life: 5 Years Field temperature: 65°C

5.0 PERFORMANCE

5.1 ELECTRICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
1	Low Level Contact Resistance (LLCR) (Initial)	EIA-364-23 – Option 1 Mate connectors: apply a current of 100 mA maximum and voltage of 20 mV maximum.	20 milliohms MAXIMUM
2	Low Level Contact Resistance (LLCR) (Change from initial)	EIA-364-23 – Option 1 Mate connectors. Apply a current of 100 mA maximum and a voltage of 20 mV maximum.	10 milliohms MAXIMUM
3	Insulation Resistance	EIA-364-21 Unmate and unmount connectors: apply a voltage of 500 VDC between adjacent terminals and between terminals to ground.	1 Megaohms MINIMUM
4	Dielectric Withstanding Voltage	EIA-364-20 – Method B Unmate connectors: apply a voltage of 500 VAC for 1 minute between adjacent terminals.	No breakdown

5.2 MECHANICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
5	Insertion Force (Module to connector with latches)	EIA-364-13 – Method B Mate a 1.50 ± 0.01 mm thickness gauge (GS-010-1) to the connector at a rate of 25.4 mm per minute.	106.8 N MAXIMUM

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5.2 MECHANICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITIO	ON	R	EQUIREME	INT		
6	Retention Force – Terminal	EIA-364-29 – Method C Axial pull-out of terminal in the maximum rate of 25.4 mm per	3	00 gf MINIM per pin	UM			
7	Retention Force – Fork lock	EIA-364-29 – Method C Axial pull-out of fork lock in th maximum rate of 25. 4 mm pe	A-364-29 – Method C xial pull-out of fork lock in the housing at a aximum rate of 25. 4 mm per minute.					
8	Durability (Preconditioning)	EIA-364-09 Perform 5 plug-and-unplug cy maximum rate of 5 cycles per	A-364-09 Prform 5 plug-and-unplug cycles at a damage damage			hysical		
9	Durability	EIA-364-09 Perform 25 plug-and-unplug c maximum rate of 5 cycles per	cycles at a minute.	No e	vidence of p damage	hysical		
10	Vibration	EIA-364-28 Mated connectors Random profile: 5 Hz @ 0.01 g ² /Hz to 20 Hz @ (slope up) 20 Hz to 500 Hz @ 0.02 g ² /Hz Input acceleration is 3.13 g RI 10 minutes per axis for all 3 a samples Random control limit tolerance Module weight 40 ± 2 g with ca 18-20 mm from module mating	0.02 g ² /Hz z (flat) MS xes on all e is ± 3 dB enter of gravity g edge.	No evidence of physical damage No discontinuities of ≥ 1 microsecond				
11	Shock (Mechanical)	Mated Connectors. Profile: Trapezoidal shock 50 Duration : 11 millisecond Velocity change : 170 " per se Quantity: Three drops in each directions. Total 18 drops per Module weight 40 ± 2 g with 18 height with center of gravity 8 module mating edge.	Mated Connectors. Profile: Trapezoidal shock 50 g, \pm 10% Duration : 11 millisecond Velocity change : 170 " per second, \pm 10% Quantity: Three drops in each of six directions. Total 18 drops per connector Module weight 40 \pm 2 g with 18.75 mm card height with center of gravity 8-10 mm from			No evidence of physical damage No discontinuities of ≥ 1 microsecond		
12	Reseating	EIA-364-09 Manually mate and unmate the connector with the module card for 3 cycles at a maximum rate of 5 cycles per minute.			hysical			
13	Latch Overstress Force	Unmated connectors: apply a force on the latch at a rate of per minute in the fully open per	Jnmated connectors: apply an actuation orce on the latch at a rate of 25.4 ± 6 mm per minute in the fully open position. 3.5 kgf MINIMUM force H 10 seconds with no da			ce held for damage		
14	Latch Actuation Force	Apply an actuation force on the rate of 25.4 ± 6 mm per minute blade of 1.50 ± 0.01 mm (GS-0 into the connector.	e latch at a e with the test 010-1) inserted	The force to fully actuate the latch open shall be 3.5 kgf MAXIMUM per latch		ctuate the e 3.5 kgf latch		
15	Module Rip-out	Pull up from the center of the	test module	9.	1kgf MINIM	UM		
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5.2 MECHANICAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CONDITION	REQUIREMENT
	Force	1.50 ± 0.01 mm thick (GS-010-1) at a rate of 25.4 ± 6 mm per minute. with the latches closed.	Retention force of the module in the connector with no damage
16	Insertion Force – Connector to board	EIA-364-05 Unmated connectors: Push connector into applicable PCB at a rate of 12.7 ± 3 mm per minute. Fork lock PCB hole size: 2.45 ± 0.05 mm	75 N MAXIMUM
17	Retention Force – Connector to board	EIA-364-05 Unmated connectors: Pull or push with a force of 0.45 kgf the connector mounted on the PCB at a rate of 12.7 ± 3 mm per minute. Fork lock PCB hole size: 2.45 ± 0.05 mm	No lifting of connector from applicable PCB
18	Unmating Force (perpinpair)	EIA-364-13 – Method B Pull out 1.30 ± 0.01 mm thick (GS-010-2) test blade from connector with latches removed at a rate of 12.7 ± 3mm per minute.	2.02 kgf MINIMUM for 288 circuits (14 gf per pin pair)

5.3 ENVIRONMENTAL REQUIREMENTS

ITEM	I DESCRIPTION	TEST CO	R	REQUIREMENT		
19	Shock (Thermal)	$\begin{array}{c c} EIA-364-32 & - Method \ A, \ Test \ Condition \ I, \\ Duration \ A-4 \\ \\ & Mate \ connectors: \ expose \ to \ 10 \ cycles \ of \\ \hline \hline \ Temperature \ (^\circC) & Duration \ (min) \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$			None	
20	Temperature Life (Preconditioning)	EIA 365-17 – Method A load) Mate connector: expos 2°C. Exposure time as per E	EIA 365-17 – Method A (without electrical load) Mate connector: expose 72 hours at 105° ± 2° C. Exposure time as per EIA-364-1000. Table 9			
21	Temperature Life	EIA 365-17 – Method A load) Mate connector: expos 2°C. Exposure time as per E	EIA 365-17 – Method A (without electrical load) Mate connector: expose 120 hours at 105° ± 2° C. Exposure time as per EIA-364-1000. Table 8			
22	Solderability	JESD22-B102 – Condi Unmated connector: Steam age for 8 hours Dip solder tails into sole temperature of 245 ± 5 seconds.	$\begin{array}{l} ESD22\-B102\-Condition\ C\\ Jnmated \ connector:\\ Steam \ age \ for \ 8 \ hours \ \pm \ 15 \ minute.\\ Dip \ solder \ tails \ into \ solder \ pot \ at \ a\\ emperature \ of \ 245 \ \pm \ 5^\circ C \ for \ 5 \ \pm \ 0.5\\ seconds. \end{array}$			M ge
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5.3 ENVIRONMENTAL REQUIREMENTS

ITEM	DESCRIPTION	TEST CO	NDITION	REQUIREMENT
		Rate: 25.4 ± 6mm per s Flux type: ROL0	second	
23	Resistance to Solder Heat	E-364-56 Dip solder tails into sold for 5 ± 1 seconds. Immerse leads to a dep from connector body.	der pot at 260 ± 5 °C oth of 1.00 ± 0.20 mm	Visual: No damage or discoloration of connector materials.
24	Temperature Rise	EIA-364-70 Ten pair contacts in color on the same side of the connected in a series of condition). A thermocol through holes in the so close to the contact inte Supply the rated current	nsecutive positions e connector are ircuit (mated uple is inserted cket housing, as erface as possible. nt.	Maximum Temperature Rise shall no exceed 30 °C above ambient
25	Cyclic Temperature & Humidity	EIA-364-1000 – Test G temperature and humic Cycle the connector be Cycle between tempe Temperature (°C) 25 ± 3 65 ± 3 Ramp times should be times should be 1 hour when the temperature a stabilized within the spe 24 such cycles	roup 2, Cyclic lity rature and RH RH (%) 80 ± 3 50 ± 3 0.5 hour and dwell . Dwell times start and humidity have ecified levels. Perform	None
26	Mixed Flowing Gas	EIA-364-65 – Class IIA Exposure time: EIA-364 Expose unmated conner MFG chamber. Expose module mated during te preconditioning) conner MFG chamber.	, 4-1000 – Table 4.1. ector for 112 hours in e mated (to same test emp life ctor for 56 hours in	None
27	Thermal Disturbance	EIA-364-1000 – Table - Mated connector. Cycle the connector be 85 ± 3° C, as measured should be a minimum of Dwell times should ens reach temperature extr of 5 minutes). No humin 10 cycles.	4. tween 15 ± 3 °C and on the part. Ramps of 2 °C per minute. Sure that contacts eme (for a minimum dity control. Perform	None

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6.0 TEST SEQUENCE

S	DESCRIPTION EQUENCE												
		1	2	3	4	5	6	7	8	9	10	11	12
Low level c (Initial)	contact resistance	1	1	1		1							1
Durability (I	Preconditioning)	2	2	2									2
Durability						2							
Low level c (Change fro	contact resistance om initial)	4,6	4,6,8	3,5,7		3							4,6,8,10,12
Insulation r	resistance				1, 5								
Dielectric w	vithstanding voltage				2,6								
Temperatur (Preconditio	re life oning)												3
Temperatu	re life	3											
Shock (The	ermal)		3		3								
Thermal dis	sturbance												9
Cyclic temp	perature & humidity		5		4								
Mixed flowi	ing gas (Unmated)												5
Mixed flowi	ing gas (Mated)												7
Shock (Med	chanical)			6									
Vibration				4									
Reseating		5	7										11
Temperatu	re rise						1						
Solderabilit	ty							1					
Resistance	to solder heat								3				
Insertion Fo	orce (Module to with latches)									1			
Latch Actua	ation Force										1		
Latch Over	stress Force										2		
Module Rip	o-out Force									2			
Insertion fo	orce – Connector to											1	
Retention for Board	orce – Connector to											2	
Retention F	Force - Terminal								1,4				
Retention F	Force – Fork lock								2,5				
Unmating F	orce (per pin pair)											3	
Sample Siz	ze per Test Group	5	5	5	5	5	5	5	6	5	5	5	5

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7.0 PACKAGING

Parts shall be packed in trays and protected against damage during handling, transportation and storage.

8.0 RECOMMENDED LEAD-FREE REFLOW PROFILES

Connector should be soldered onto PCB using either the wave soldering technique or the reflow soldering technique according to the table shown below.

Process	Peak Temperature	Duration
Wave	265°C MAXIMUM (Solder Batch) 220°C MAXIMUM Connector housing	5 ± 2 second (wave contact)
Reflow	220°C MAXIMUM Peak 220°C MAXIMUM Connector housing	20 to 40 seconds Time within 5 °C of peak

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